

**Search Notes**

Application/Control No.

10/574,933

Examiner

Tuan Quach

Applicant(s)/Patent under  
Reexamination

NAKAYAMA ET AL.

Art Unit

2826

**SEARCHED**

Class	Subclass	Date	Examiner
257	734, 765, 768-771, E23.159	9/2/2007	TQ
257	E21.161	9/2/2007	TQ
438	656, 660	9/2/2007	TQ
438	686	9/2/2007	TQ

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
EAST - USPAT; USPGPUB - see interference search printout		9/2/2007	TQ

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (USPAT; USPGPUB; EPO; JPO; DERWENT; IBMTDB) see search history printout	9/2/2007	TQ
EAST -USPAT; USPGPUB see interference search printout	9/2/2007	TQ